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# Single P-Channel PowerTrench<sup>®</sup> MOSFET -12 V, -10 A, 16 m $\Omega$

### Features

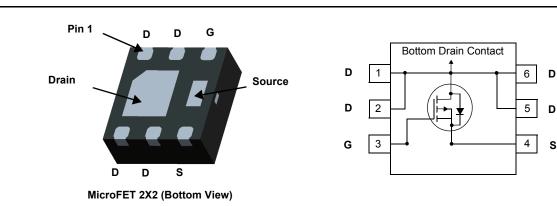
- Max r<sub>DS(on)</sub> = 16 mΩ at V<sub>GS</sub> = -4.5 V, I<sub>D</sub> = -10 A
- Max r<sub>DS(on)</sub> = 21 mΩ at V<sub>GS</sub> = -2.5 V, I<sub>D</sub> = -8.9 A
- Max  $r_{DS(on)}$  = 82 m $\Omega$  at V<sub>GS</sub> = -1.8 V, I<sub>D</sub> = -4.5 A
- Low profile 0.8 mm maximum in the new package MicroFET 2X2 mm
- Free from halogenated compounds and antimony oxides
- RoHS Compliant



# **General Description**

This device is designed specifically for battery charge or load switching in cellular handset and other ultraportable applications. It features a MOSFET with low on-state resistance.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.



## MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage		-12	V	
V <sub>GS</sub>	Gate to Source Voltage		±8	V	
1	Drain Current -Continuous	(Note 1a)	-10	•	
D	-Pulsed		-40	Α	
D	Power Dissipation	(Note 1a)	2.4	w	
PD	Power Dissipation	(Note 1b)	0.9		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C	

#### **Thermal Characteristics**

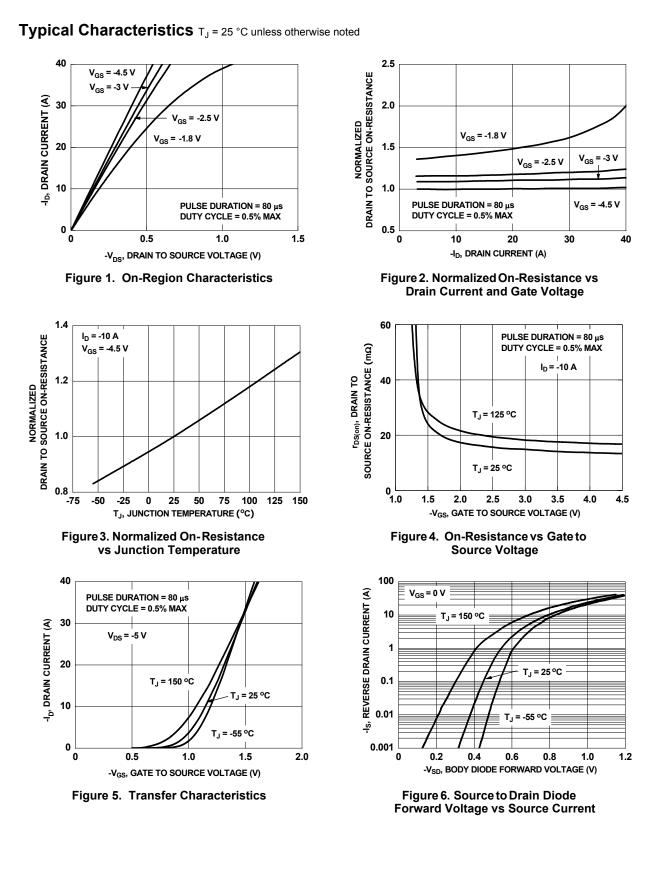
$R_{\theta JC}$	Thermal Resistance, Junction to Case		6.9	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient (Note	e 1a)	52	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note	e 1b)	145	

#### Package Marking and Ordering Information

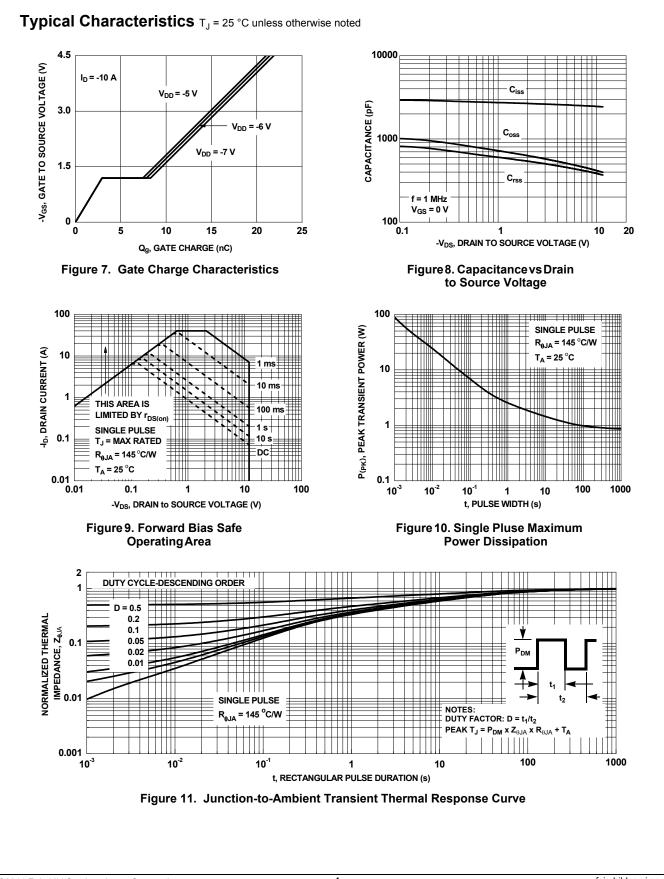
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
A95	FDMA905P	MicroFET 2X2	7 "	8 mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0V	-12			V
ΔBV <sub>DSS</sub> ΔTJ	Breakdown Voltage Temperature	$I_D = -250 \ \mu$ A, referenced to 25 °C		-4.3		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -9.6 V, V <sub>GS</sub> = 0 V			-1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 V, V_{DS} = 0 V$			±100	nA
	cteristics			• •		
			-0.4	0.7	1.0	V
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \ \mu A$	-0.4	-0.7	-1.0	v
$rac{\Delta V_{GS(th)}}{\Delta T_J}$	Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		2.6		mV/°C
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -10 A		14	16	
-	Statia Drain ta Sauraa On Dagiatanga	V <sub>GS</sub> = -2.5 V, I <sub>D</sub> = -8.9 A		17	21	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = -1.8 V, I <sub>D</sub> = -4.5 A		21	82	mΩ
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -10 A, T <sub>J</sub> = 125 °C		16	21	1
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = -5 V, I <sub>D</sub> = -10 A		50		S
Dvnamic	Characteristics					
C <sub>iss</sub>	Input Capacitance			2559	3405	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = -6 V, V <sub>GS</sub> = 0 V,		490	735	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1 MHz		437	655	pF
						р.
Switching	Characteristics	1				
t <sub>d(on)</sub>	Turn-On Delay Time	_		11	20	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = -6 V, I <sub>D</sub> = -10 A,		11	20	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = -4.5 V, $R_{GEN}$ = 6 $\Omega$		120	192	ns
t <sub>f</sub>	Fall Time			59	94	ns
Qg	Total Gate Charge	– V <sub>DD</sub> = -6 V, I <sub>D</sub> = -10 A,		21	29	nC
Q <sub>gs</sub>	Gate to Source Charge	$V_{GS} = -4.5 V$		3.5		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			4.2		nC
Drain-Sou	urce Diode Characteristics					
. ,		$V_{GS} = 0 V, I_S = -2 A$ (Note 2)		-0.6	-1.2	
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = -10 A$ (Note 2)		-0.8	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time			21	34	ns
Q <sub>rr</sub>	Reverse Recovery Charge	–I <sub>F</sub> = -10 A, di/dt = 100 A/μs		6.1	12	nC
lotes: . R <sub>θJA</sub> is determ the user's boz	nined with the device mounted on a 1 in <sup>2</sup> pad 2 oz copper p rrd design. a. 52 °C/W when mo a 1 in <sup>2</sup> pad of 2 oz	unted on b	. 145 °C/W v	by design whil	ion a	etermined by
2. Pulse Test: Pi	ulse Width < 300 $\mu$ s, Duty cycle < 2.0 %.					
•						

FDMA905P Single P-Channel PowerTrench<sup>®</sup> MOSFET



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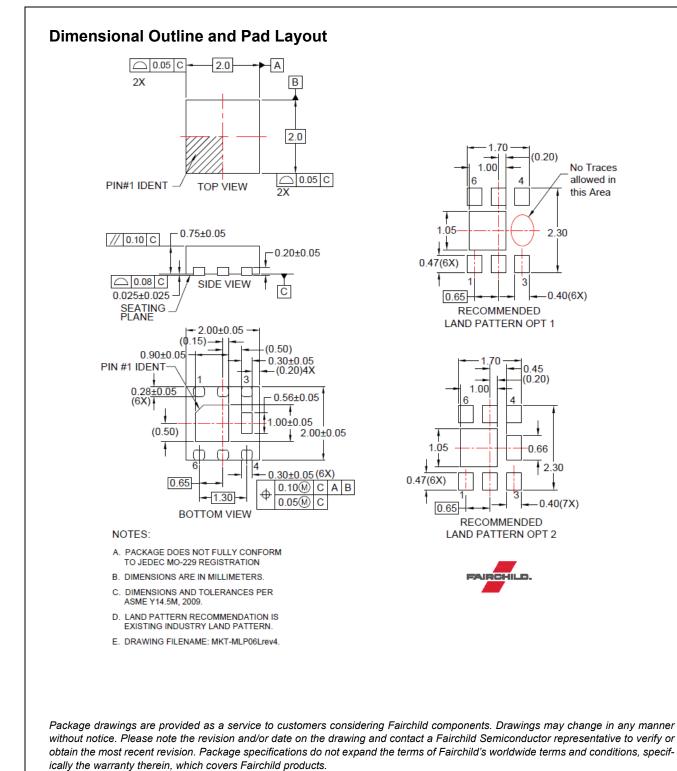
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